

100V N-Channel Power MOSFET

Description

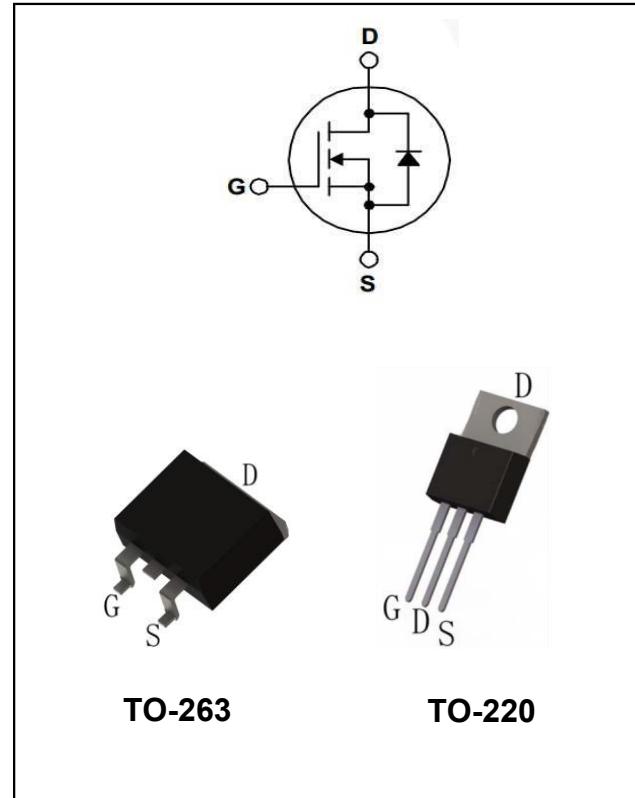
MPT028N10, the N-channel Enhanced Power MOSFETs, is obtained by advanced double trench technology which reduce the conduction loss, improve switching performance and enhance the avalanche energy. This is suitable device for BMS and high current switching applications.

General Features

- ① $V_{DS}=100V$, $R_{dson}<3m\Omega$ @ $V_{GS}=10V$, $I_D=180A$ (Typ:2.7mΩ)
- ② Fast Switching
- ③ Low On-Resistance
- ④ Low Gate Charge
- ⑤ Low Reverse transfer capacitances
- ⑥ High avalanche ruggedness
- ⑦ RoHS product

Application

- ① BMS
- ② High current switching applications



Package Marking And Ordering Information:

Ordering Codes	Package	Product Code	Packing
MPT028N10-P	TO-220	028N10	Tube
MPT028N10-S	TO-263	028N10	Tape Reel

ABSOLUTE RATINGS at $TC=25^{\circ}C$, unless otherwise specified

Symbol	Parameter	Rating	Units
V_{DSS}	Drain-Source Voltage	100	V
I_D	Continuous Drain Current, Silicon Limited	200	A
	Continuous Drain Current, Package Limited	180	A
	Continuous Drain Current @ $T_c=100^{\circ}C$, Silicon Limited	126.6	A
I_{DM} Note1	Pulsed Drain Current	720	A
V_{GS}	Gate-Source Voltage	± 20	V



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E _{AS} ^{Note2}	Avalanche Energy	784	mJ
P _D	Power Dissipation	250	W
	Derating Factor above 25°C	2	W/°C
T _J , T _{stg}	Operating Junction and Storage Temperature Range	150, -55 to 150	°C
T _L	Maximum Temperature for Soldering	260	°C

Note1: Repetitive Rating: Pulse width limited by maximum junction temperature Note2: L=0.5mH, I_{as}=35A, Start T_J=25°C

Thermal characteristics

Symbol	Parameter	Max	Units
R _{θJC}	thermal resistance, Junction-Case	0.5	°C/W
R _{θJA}	thermal resistance, Junction-Ambient	62.5	°C/W

Electrical Characteristics at T_c=25°C, unless otherwise specified

OFF Characteristics						
Symbol	Parameter	Test Conditions	Values			Units
			Min	Typ	Max	
V _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D =250μA	100	110	--	V
I _{DSS}	Drain-Source Leakage Current	V _{DS} =100V, V _{GS} =0V	--	--	1	μA
		V _{DS} =80V, V _{GS} =0V @T _c =125°C	--	--	100	μA
I _{GSS(F)}	Gate-Source Forward Leakage	V _{GS} =+20V	--	--	100	nA
I _{GSS(R)}	Gate-Source Reverse Leakage	V _{GS} =-20V	--	--	-100	nA

ON Characteristics						
Symbol	Parameter	Test Conditions	Values			Unit s
			Min	Typ	Max	
R _{DS(on)}	Drain-Source On-Resistance	V _{GS} =10V, I _D =50A	--	2.7	3	mΩ
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =250μA	2.0	3.0	4.0	V
Pulse width tp≤300μs, δ≤2%						

Dynamic Characteristics						
Symbol	Parameter	Test Conditions	Values			Units
			Min	Typ	Max	
C _{iss}	Input Capacitance	V _{DS} =50V, V _{GS} =0, f=1MHz	--	9200	--	pF
C _{oss}	Output Capacitance		--	1130	--	
C _{rss}	Reverse Transfer Capacitance		--	110	--	



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Q_g	Total Gate Charge	$V_{DD}=50V$, $I_D=92.5A$, $V_{GS}=10V$	--	131	--	nC
Q_{gs}	Gate-Source charge		--	50	--	
Q_{gd}	Gate-Drain charge		--	24.5	--	

Switching Characteristics

Symbol	Parameter	Test Conditions	Values			Units
			Min	Typ	Max	
$t_{d(on)}$	Turn-On Delay Time	$V_{DD}=50V$, $V_{GS}=10V$, $R_G=1.6\Omega$, Resistive Load	--	32	--	ns
t_r	Rise Time		--	40	--	
$t_{d(off)}$	Turn-Off Delay Time		--	80	--	
t_f	Fall Time		--	35	--	

Source-Drain Diode Characteristics

Symbol	Parameter	Test Conditions	Values			Units
			Min	Typ	Max	
I_s	Continuous Source Current	$V_{GS}=0V$, $I_s=50A$	--	--	180	A
I_{SM}	Maximum Pulsed Current		--	--	720	A
V_{SD}	Diode Forward Voltage	$V_{GS}=0V$, $I_s=50A$	--	--	1.2	V
T_{rr}	Reverse Recovery Time	$I_s=92.5A$, $dI/dt=100A/\mu s$	--	80	--	ns
Q_{rr}	Reverse Recovery Charge		--	195	--	uC

Characteristics Curves

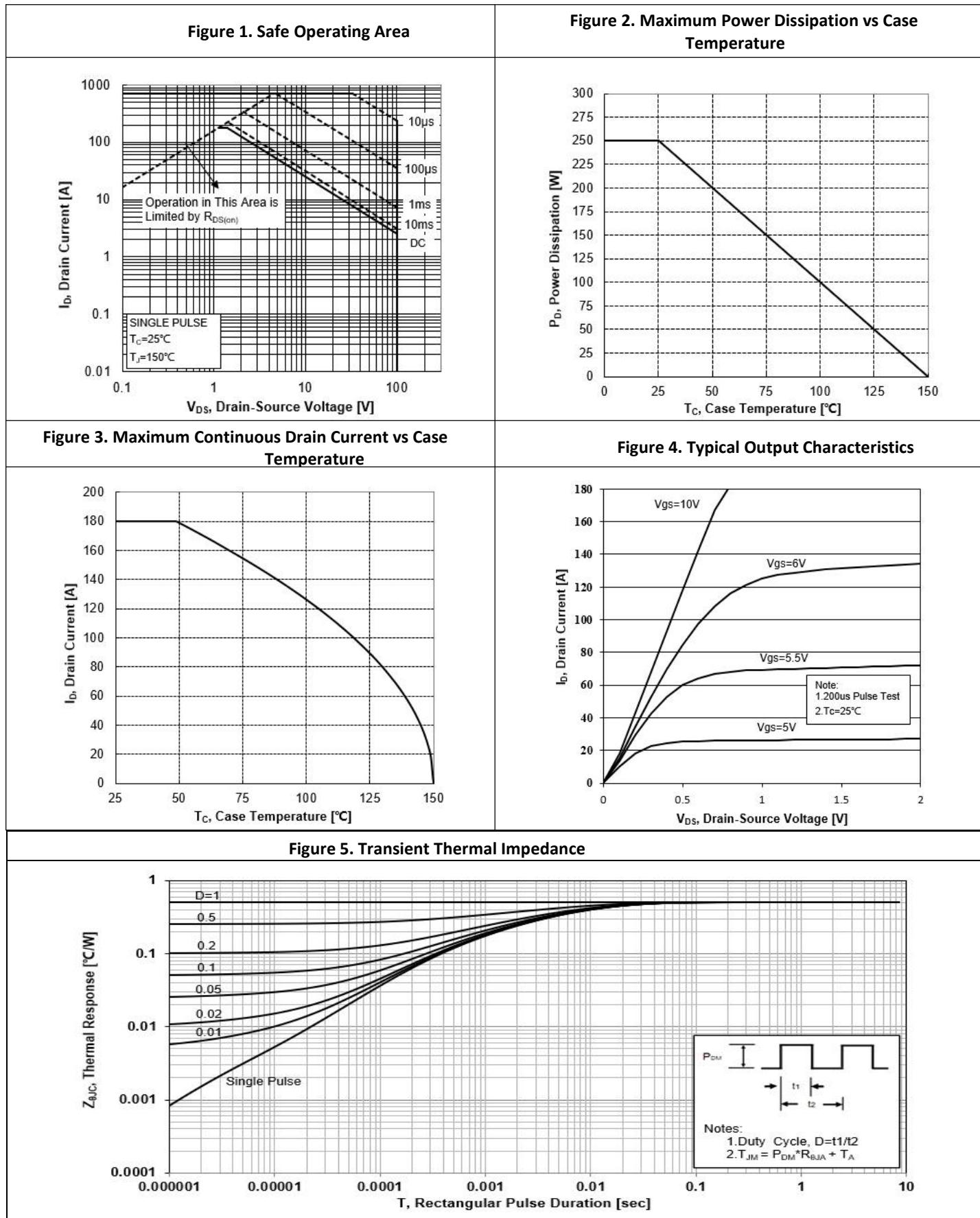


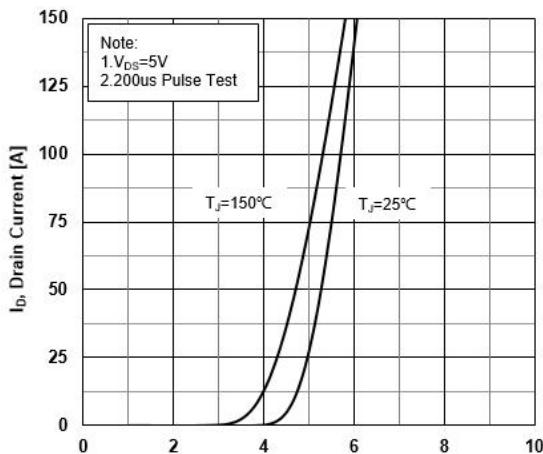
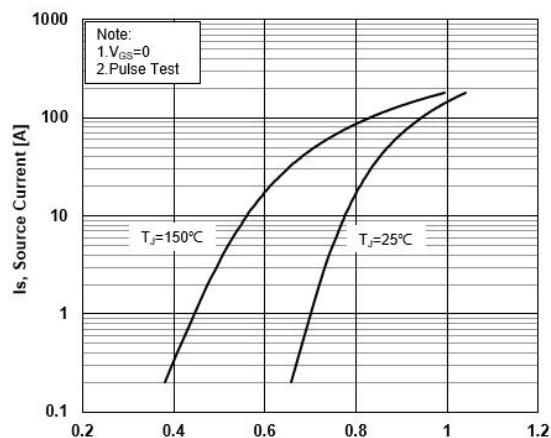
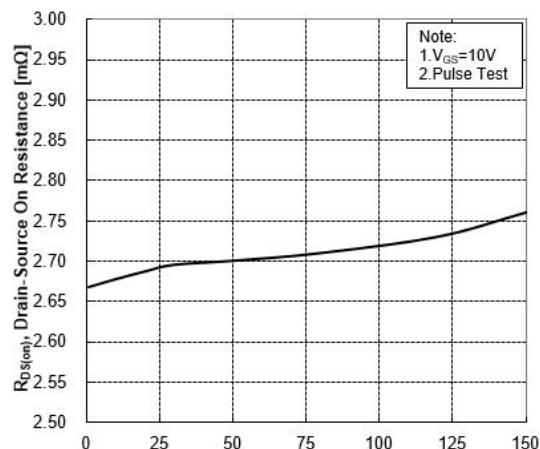
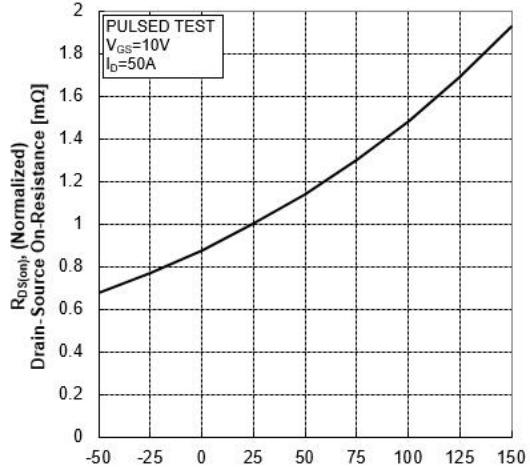
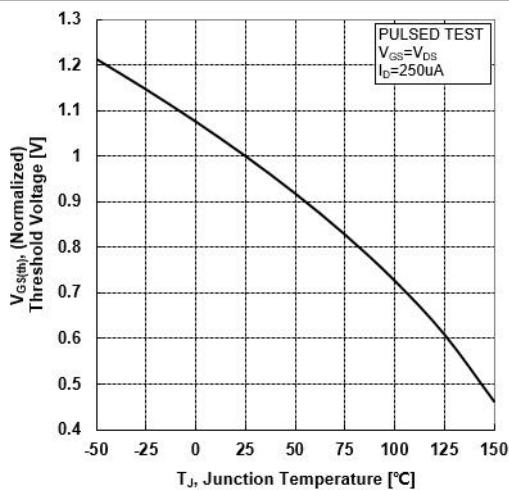
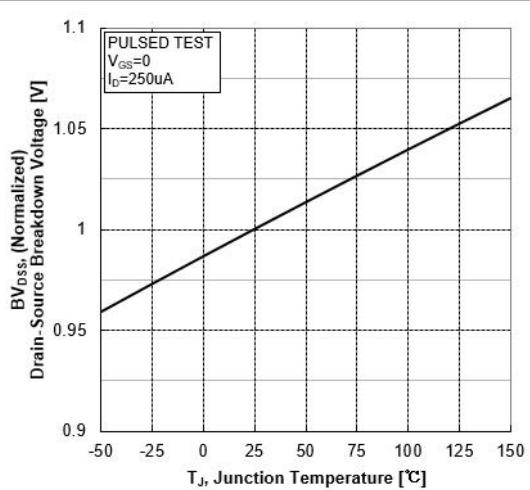
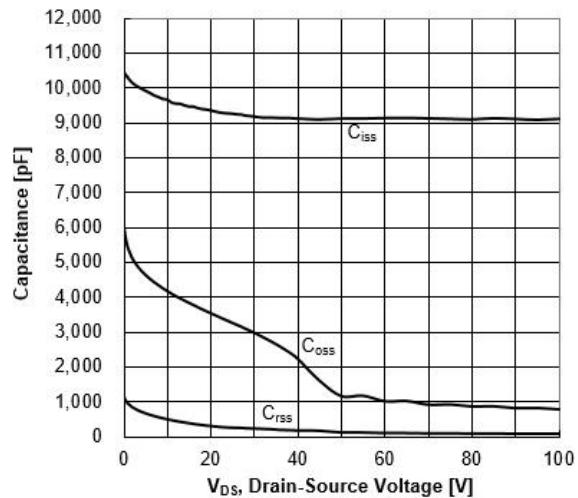
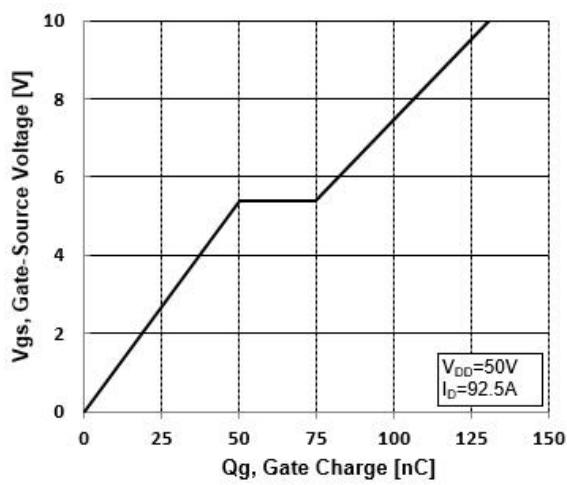
Figure 6. Typical Transfer Characteristics

Figure 7. Source-Drain Diode Forward Characteristics

Figure 8. Drain-Source On-Resistance vs Drain Current

Figure 9. Normalized On-Resistance vs Junction Temperature

Figure 10. Normalized Threshold Voltage vs Junction Temperature

Figure 11. Normalized Breakdown Voltage vs Junction Temperature


Figure 12. Capacitance Characteristics

Figure 13. Typical Gate Charge vs Gate-Source Voltage


Test Circuit and Waveform

Figure 14. Resistive Switching Test Circuit

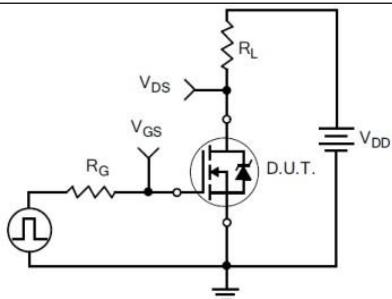


Figure 15. Resistive Switching Waveforms

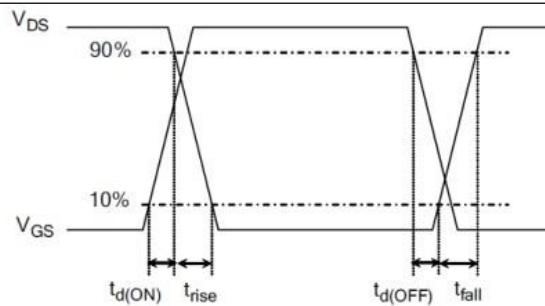


Figure 16. Gate Charge Test Circuit

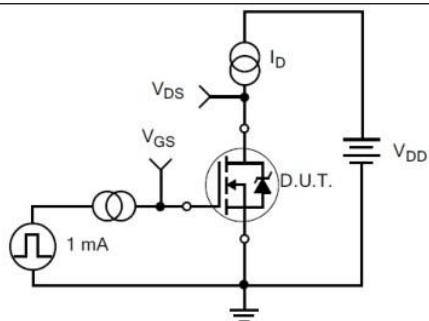


Figure 17. Gate Charge Waveforms

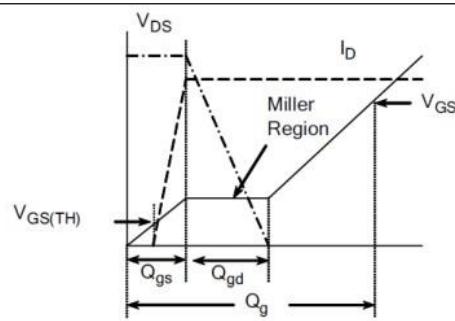


Figure 18. Diode Reverse Recovery Test Circuit

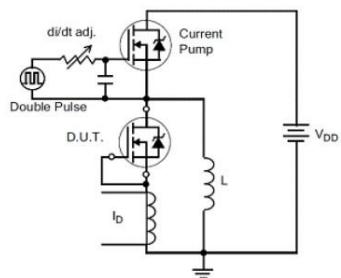


Figure 19. Diode Reverse Recovery Waveform

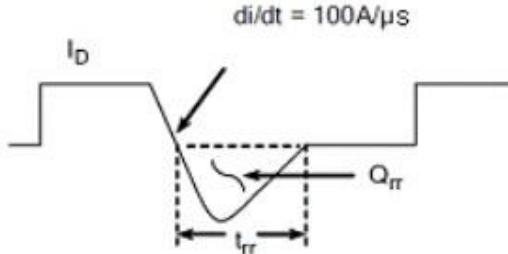


Figure 20. Unclamped Inductive Switching Test Circuit

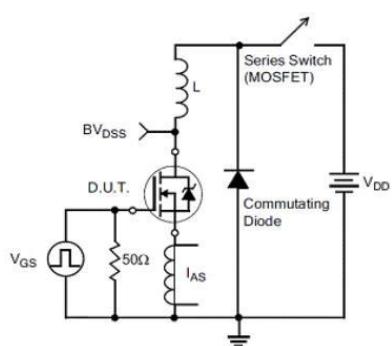
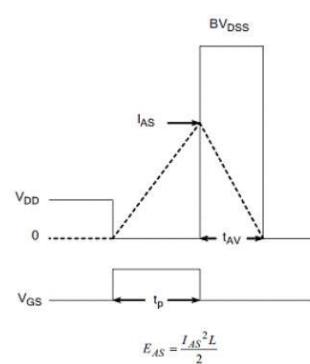


Figure 21. Unclamped Inductive Switching Waveform

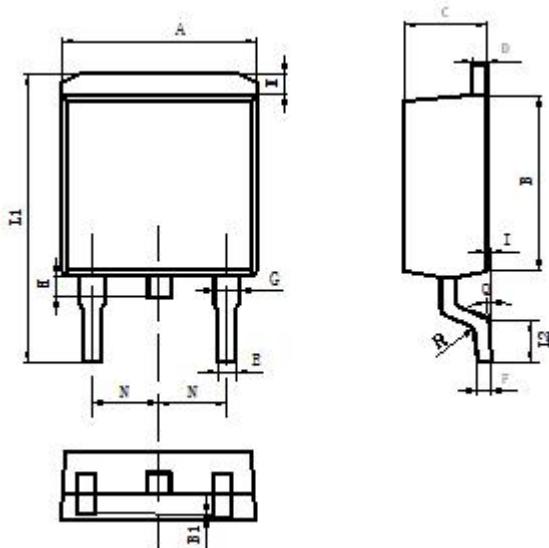




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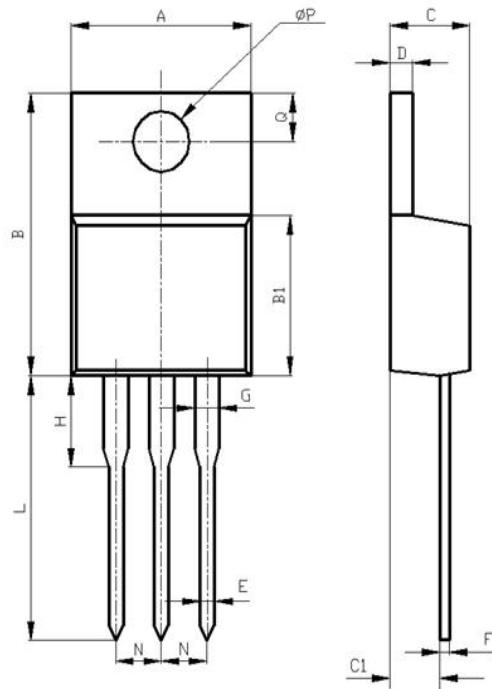
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Package Description



Items	Values(mm)	
	MIN	MAX
A	9.80	10.40
B	8.90	9.50
B1	0	0.10
C	4.40	4.80
D	1.16	1.37
E	0.70	0.95
F	0.30	0.60
G	1.07	1.47
H	1.30	1.80
K	0.95	1.37
L1	14.50	16.50
L2	1.60	2.30
I	0	0.2
Q	0°	8°
R		0.4
N	2.39	2.69

TO-263 Package



Items	Values(mm)	
	MIN	MAX
A	9.60	10.6
B	15.0	16.0
B1	8.90	9.50
C	4.30	4.80
C1	2.30	3.10
D	1.20	1.40
E	0.70	0.90
F	0.30	0.60
G	1.17	1.37
H	2.70	3.80
L	12.6	14.8
N	2.34	2.74
Q	2.40	3.00
ϕP	3.50	3.90

TO-220 Package

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NOTE:

1. Exceeding the maximum ratings of the device in performance may cause damage to the device, even the permanent failure, which may affect the dependability of the machine. Please do not exceed the absolute maximum ratings of the device when circuit designing.
2. When installing the heat sink, please pay attention to the torsional moment and the smoothness of the heat sink.
3. MOSFETs is the device which is sensitive to the static electricity, it is necessary to protect the device from being damaged by the static electricity when using it.
4. Shenzhen Minos reserves the right to make changes in this specification sheet and is subject to change without prior notice.

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